



KM416S1120AT  
SDRAM

### 512K x 16Bit x 2 Bank Synchronous DRAM

#### FEATURES

- JEDEC standard 3.3V Power Supply.
- LVTTTL compatible with multiplexed address.
- Dual Bank.
- MRS cycle with address key programs.
  - CAS Latency (1, 2, 3)
  - Burst Length (1, 2, 4, 8 & Full page)
  - Burst Type (Sequential & Interleave)
- All inputs are sampled at the positive going edge of the system clock.
- Burst Read Single Bit Write Operation.
- L(U)DQM for byte masking.
- Auto & Self Refresh.
- 32ms Refresh Period. (2K cycle)

#### GENERAL DESCRIPTION

The KM416S1120A is 16,777,216 bits synchronous high data rate Dynamic RAM organized as 2 x 524,288 words by 16 bits, fabricated with SAMSUNG's high performance CMOS technology.

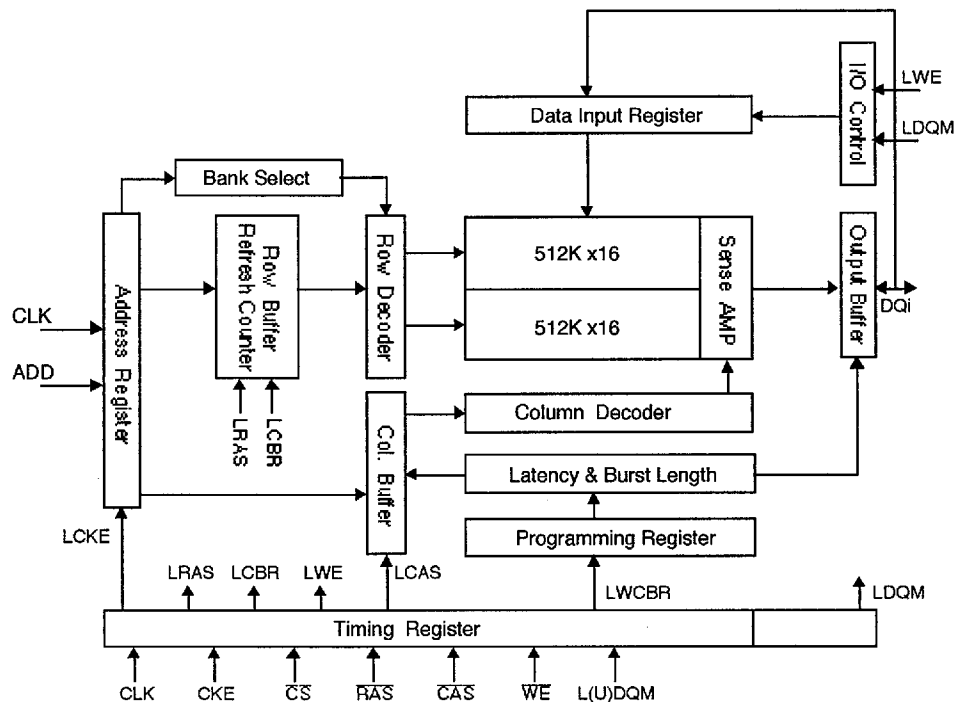
Synchronous design allows precise cycle control with the use of system clock. I/O transactions are possible on every clock cycle.

Range of operating frequencies, programmable burst length, and programmable latencies allows the same device to be useful for a variety of high bandwidth, high performance memory system applications.

#### ORDERING INFORMATION

Part NO.	Max Freq.	Package
KM416S1120AT-G/F10	100 MHz	TSOP (II)
KM416S1120AT-G/F12	83 MHz	TSOP (II)

#### FUNCTIONAL BLOCK DIAGRAM





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### PIN CONFIGURATION (Top View)

VDD	1	50	Vss
DQ0	2	49	DQ15
DQ1	3	48	DQ14
VSSQ	4	47	VSSQ
DQ2	5	46	DQ13
DQ3	6	45	DQ12
VDDQ	7	44	VDDQ
DQ4	8	43	DQ11
DQ5	9	42	DQ10
VSSQ	10	41	VSSQ
DQ6	11	40	DQ9
DQ7	12	39	DQ8
VDDQ	13	38	VDDQ
LDQM	14	37	N.C
WE	15	36	UDQM
CAS	16	35	CLK
RAS	17	34	CKE
CS	18	33	N.C
A11	19	32	A9
A10	20	31	A8
A0	21	30	A7
A1	22	29	A6
A2	23	28	A5
A3	24	27	A4
VDD	25	26	Vss

50 PIN TSOP (II)  
(400mil x 825mil)  
(0.8 mm PIN PITCH)

### PIN FUNCTION DESCRIPTION

PIN	NAME	INPUT FUNCTION
CLK	System Clock	Active on the positive going edge to sample all inputs.
$\overline{CS}$	Chip Select	Disables or enables device operation by masking or enabling all inputs except CLK, CKE, and L(U)DQM
CKE	Clock Enable	Masks system clock to freeze operation from the next clock cycle. CKE should be enabled at least one cycle prior to new command. Disables input buffers for power down in standby. CKE should be enabled tPDE prior to valid command.
A0 ~ A10	Address	Row / column addresses are multiplexed on the same pins. Row address : RA0 ~ RA10, Column address : CA0 ~ CA7
A11	Bank Select Address	Selects bank to be activated during row address latch time. Selects bank for read/write during column address latch time.
$\overline{RAS}$	Row Address Strobe	Latches row addresses on the positive going edge of the CLK with $\overline{RAS}$ low. Enables row access & precharge.
$\overline{CAS}$	Column Address Strobe	Latches column addresses on the positive going edge of the CLK with $\overline{CAS}$ low. Enables column access.
WE	Write Enable	Enables write operation and row precharge.
L(U)DQM	Data Input/Output Mask	Makes data output Hi-Z, tSHZ after the clock and masks the output. Blocks data input when DQM active. (Byte Masking)
DQ0 ~ 15	Data Input/Output	Data inputs/outputs are multiplexed on the same pins.
VDD/Vss	Power Supply/Ground	
VDDQ/VSSQ	Data Output Power/Ground	



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## ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Voltage on any pin relative to Vss	VIN, VOUT	-1.0 ~ 4.6	V
Voltage on VDD supply relative to Vss	VDD, VDDQ	-1.0 ~ 4.6	V
Storage temperature	TSTG	-55 ~ +150	°C
Power dissipation	Pd	1	W
Short circuit current	Ios	50	mA

**Note :** Permanent device damage may occur if 'ABSOLUTE MAXIMUM RATINGS' are exceeded.  
Functional operation should be restricted to recommended operating condition.  
Exposure to higher than recommended voltage for extended periods of time could affect device reliability.

## DC OPERATING CONDITIONS

Recommended operating conditions (Voltages referenced to Vss = 0V, TA=0°C to 70°C)

Parameter	Symbol	Min.	Typ	Max.	Unit	Note
Supply voltage	VDD, VDDQ	3.0	3.3	3.6	V	
Input high voltage	VIH	2.0	3.0	VDD+0.3	V	
Input low voltage	VIL	-0.3	0	0.8	V	Note 1
Output high voltage	VOH	2.4	-	-	V	IOH = -2mA
Output low voltage	VOL	-	-	0.4	V	IOL = 2mA
Input leakage current	IIL	-5	-	5	uA	Note 2
Output leakage current	IOL	-5	-	5	uA	Note 3

**Note :** 1. VIL(min.) = -1.5V AC (pulse width ≤ 5 ns)  
2. Any input 0 ≤ VIN ≤ VDD + 0.3V, all other pins are not under test = 0V.  
3. Dout is disabled, 0V ≤ VOUT ≤ VDD.

## CAPACITANCE (VDD= 3.3V, TA= 25°C, f= 1MHz)

Parameter	Symbol	Min	Max	Unit
Input capacitance (A0 ~ A11)	CIN1	-	5	pF
Input capacitance (CLK,CKE,CS, RAS,CAS,WE & L(U)DQM)	CIN2	-	5	pF
Data input/output capacitance (DQ0 ~ DQ15)	COU	-	6	pF

## DECOUPLING CAPACITANCE GUIDE LINE

Recommended decoupling capacitors are added to power line on PCB.

Parameter	Symbol	Value	Unit
Decoupling Capacitance between VDD and Vss	CDC1	0.1 * 3	uF
Decoupling Capacitance between VDDQ and VSSQ	CDC2	0.1 * 3	uF

**Note :** 1. VDD and VDDQ pins are separated each other.  
All VDD pins are connected inside the chip. All VDDQ pins are connected inside the chip.  
2. Vss and VSSQ pins are separated each other.  
All Vss pins are connected inside the chip.

**DC CHARACTERISTICS**

( Recommended Operating Conditions Unless Otherwise Noted, TA = 0 to 70 °C )

Parameter	Symbol	Test Condition	CAS Latency	Version		Unit	Note
				-10	-12		
Operating Current	Icc1	Burst Length =1 tRC ≥ tRC(min) IOL = 0 mA	3	105	100	mA	1
			2	95	90		
			1	90	85		
Precharge Standby Current in Power-down mode	Icc2P	CKE ≤ VIH(max), tCC = 15ns	3		mA		
	Icc2PS	CKE & CLK ≤ VIH(max), tCC = ∞	2				
Precharge Standby Current in Non power-down mode	Icc2N	CKE ≥ VIH(min), CS ≥ VIH(min), tCC = 15ns Input signals are changed one time during 30ns	25		mA		
	Icc2NS	CKE ≥ VIH(min), CLK ≤ VIH(max), tCC = ∞ Input signals are stable	8				
Active Standby Current in power-down mode	Icc3P	CKE ≤ VIH(max), tCC = 15ns	3		mA		
	Icc3PS	CKE & CLK ≤ VIH(max), tCC = ∞	2				
Active Standby Current in Non power-down mode (One Bank Active)	Icc3N	CKE ≥ VIH(min), CS ≥ VIH(min), tCC = 15ns Input signals are changed one time during 30ns	30		mA		
	Icc3NS	CKE ≥ VIH(min), CLK ≤ VIH(max), tCC = ∞ Input signals are stable	15				
Operating Current (Burst Mode)	Icc4	IOL = 0 mA Page Burst All Banks activated tCCD = tCCD(min)	3	145	125	mA	1, 2
			2	105	90		
			1	65	60		
Refresh Current	Icc5	tRC ≥ tRC(min)	3	95	90	mA	3
			2	90	85		
			1	85	80		
Self Refresh Current	Icc6	CKE ≤ 0.2V	2		mA	4	
			250				uA

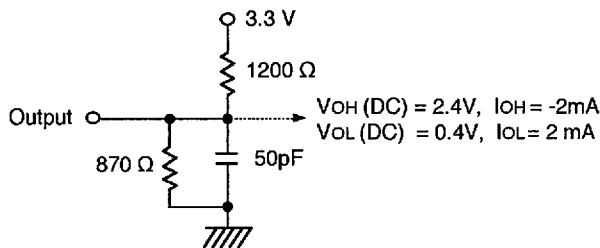
- Note :**
1. Measured with outputs open.
  2. Assumes minimum column address update cycle tCCD(min)
  3. Refresh period is 32ms.
  4. KM416S1120AT-G\*\*
  5. KM416S1120AT-F\*\*



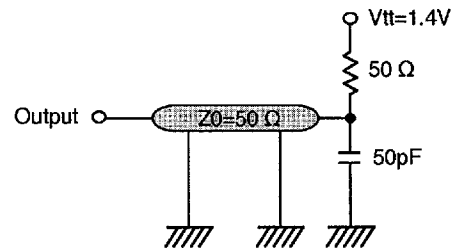
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### AC OPERATING TEST CONDITIONS (V<sub>DD</sub> = 3.3V±0.3V, T<sub>A</sub> = 0 to 70 °C)

Parameter	Value
AC input levels	V <sub>IH</sub> /V <sub>IL</sub> = 2.4V / 0.4V
Input timing measurement reference level	1.4V
Input rise and fall time	t <sub>r</sub> / t <sub>f</sub> = 1ns / 1ns
Output measurement reference level	1.4V
Output load condition	See Fig. 2



( Fig. 1 ) DC Output Load Circuit



( Fig. 2 ) AC Output Load Circuit

### OPERATING AC PARAMETER

(AC operating conditions unless otherwise noted)

Parameter	Symbol	Version		Unit	Note
		- 10	- 12		
Row active to Row active delay	tRRD(min)	20	24	ns	1
RAS to CAS delay	tRCD(min)	26	30	ns	1
Row precharge time	tRP(min)	26	30	ns	1
Row active time	tRAS(min)	60	66	ns	1
	tRAS(max)	200	200	us	
Row cycle time	tRC(min)	96	100	ns	1
Last data in to new col. address delay	tCDL(min)	1		CLK	2
Last data in to Row precharge	tRDL(min)	1		CLK	2
Last data in to burst stop	tBDL(min)	0		CLK	2
Col. address to col. address delay	tCCD(min)	1		CLK	3
Number of valid output data	CAS Latency= 3	2		ea	4
	CAS Latency= 2	1			
	CAS Latency= 1	0			

- Note :**
1. The minimum number of clock cycles is determined by dividing the minimum time required with clock cycle time, and then rounding off to the next higher integer.
  2. Minimum delay is required to complete write.
  3. All parts allow every cycle column address change.
  4. In case of Row precharge interrupt, Auto precharge and Read burst stop.

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